

Docket No.: 58647-156

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of	:	Customer Number: 20277
Takeshi IJIMA, et al.	:	
Serial No.: Continuation of	:	
Appln. Serial No. 09/894,512	:	Group Art Unit: Not yet assigned
Filed: August 04, 2003	:	Examiner: Not yet assigned
For:	:	
BIOELECTRICAL IMPEDANCE MEASURING APPARATUS	:	

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The references were cited by or submitted to the U.S. Patent and Trademark Office in parent application Serial No. 09/894,512, filed June 29, 2001, which is relied upon for an earlier filing date under 35 USC 120. Thus, copies of these references are not attached. 37 CFR 1.98(d).

Respectfully submitted,

MCDERMOTT, WILL & EMERY

*Michael A. Messina*

Michael A. Messina  
Registration No. 33,424

600 13<sup>th</sup> Street, N.W.  
Washington, DC 20005-3096  
(202) 756-8000 MAM:blp  
Facsimile: (202) 756-8087  
**Date: August 4, 2003**

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

 ATTY. DOCKET NO.  
**58647-156**

 SERIAL NO.  
 [case\_serial\_number]

 APPLICANT  
**Takeshi IJIMA, et al.**

 FILING DATE  
**August 04, 2003**

 GROUP  
 [case\_group\_art]

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US 6,456,873 B1	09/2002	Inoue et al.	
		US 6,370,425 B1	04/2002	Oguma	
		US 6,472,888 B2	10/2002	Oguma et al.	
		US 6,354,996 B1	3/2002	Drinan et al.	
		US 6,360,124 B1	3/2002	Iwabuchi	
		US 6,327,495 B1	12/2001	Iwabuchi et al.	
		US 6,473,641 B1	10/2002	Kodama et al.	
		US 6,256,532 B1	07/2001	Cha	

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP 2000-135204	5/2000				
		JP 10-174680	6/1998				
		JP 62169023	7/1987				
		JP 2000166890	6/2000				
		WO 99/20175	4/1999				
		EP 1 031 317	8/2000				
		WO 99/52425	10/1999				

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Related Appln. No. 09/510,231, filed February 22, 2000

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.